

Search Notes

Application/Control No.

10/722,178

Examiner

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Applicant(s)/Patent under
Reexamination

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Art Unit

2816

SEARCHED

Class	Subclass	Date	Examiner
331	16,17	4/18/2005	HLN
327	311,312		
327	551-559		
Update	Search	9/30/2005	HLN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR